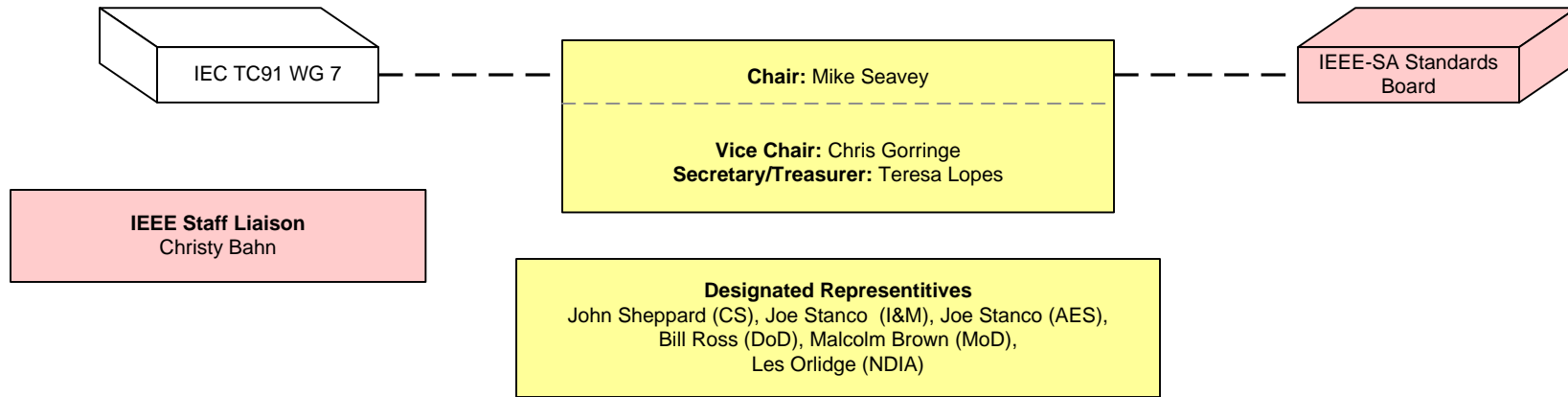


SCC20 Organization – January 2016



IEEE-P1445
DTIF
Revision of IEEE-1445-1998 (R2010)

WG Chair: Mike Seavey

IEEE-P1636
SIMICA
Revision of IEEE-1636-2009

WG Chair: John Sheppard

IEEE-P1671.1
ATML: Test Description
Revision of IEEE-1671.1-2009

WG Chair: Anand Jain

IEEE-P1505.1
Common Test Interface Pin Map Configuration
Revision of IEEE-1505.1-2008

WG Chair: Rob Spinner

IEEE-P1636.2
SIMICA: MAI
Revision of IEEE-1636.2-2010

WG Chair: John Sheppard

IEEE-P1671.3
ATML: UUT Description
Revision of IEEE-1671.1-2007

WG Chair: Ion Naeg

IEEE-P1514
Fixtures Applied to Generic Test Interfaces
New Recommended Practice

WG Chair: Steve Mann

IEEE-P1641.1a
Amendment to IEEE-1641.1
New Amendment

WG Chair: Ion Naeg

IEEE-P1871.2
Intrinsic Signal Path Information
New Recommended Practice

WG Chair: Chris Gorringe

Active Working Groups (Revision to a Published Standard or Development of the Initial Standard)

IEEE-448.1-2003

IEEE-448.2-1992

IEEE-716-1995 (R2011)

IEEE-771-1998 (R2009)

IEEE-1155-1992

IEEE-1174-2000

IEEE-1232-2010

IEEE-1232.3-2014

IEEE-1505-2010

IEEE-1505.3-2015

IEEE-1546-2000 (R2011)

IEEE-1636.1-2013

IEEE-1636.99-2013

IEEE-1641-2010

IEEE-1641.1-2013

IEEE-1671-2010

IEEE-1671.2-2012

IEEE-1671.4-2014

IEEE-1671.5-2015

IEEE-1671.6-2015

IEEE-1871.1-2014

Published IEEE Standards (Maintained By SCC20)